International Rectifier

- Logic-Level Gate Drive
- Ultra Low On-Resistance
- Surface Mount (IRLR3103)
- Straight Lead (IRLU3103)
- Advanced Process Technology
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

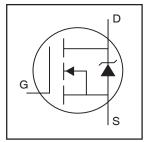
Description

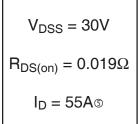
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve the lowest possible on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient device for use in a wide variety of applications.

The D-PAK is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU series) is for throughhole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.

PD - 95085A IRLR/U3103PbF

HEXFET® Power MOSFET







Absolute Maximum Ratings

	Parameter	Max.	Units	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	55®		
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	39⑤	A	
I _{DM}	Pulsed Drain Current ①⑦	220		
P _D @T _C = 25°C	Power Dissipation	107	W	
	Linear Derating Factor	0.71	W/°C	
V _{GS}	Gate-to-Source Voltage	± 16	V	
E _{AS}	Single Pulse Avalanche Energy@⑦	240	mJ	
I _{AR}	Avalanche Current ⊕ ⑦	34	A	
E _{AR}	Repetitive Avalanche Energy⊕⊘	11	mJ	
dv/dt	Peak Diode Recovery dv/dt 3	5.0	V/ns	
T _J	Operating Junction and	-55 to + 175		
T _{STG}	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.4	
$R_{\theta JA}$	Junction-to-Ambient (PCB mount) **		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

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Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions	
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	30			V	$V_{GS} = 0V, I_D = 250\mu A$	
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.037		V/°C	Reference to 25°C, I _D = 1mA	
_				0.019		V _{GS} = 10V, I _D = 33A ⊕	
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.024	Ω	V _{GS} = 4.5V, I _D = 25A ④	
V _{GS(th)}	Gate Threshold Voltage	1.0			V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
9 fs	Forward Transconductance	23			S	V _{DS} = 25V, I _D = 34A⑦	
1	Drain-to-Source Leakage Current			25		$V_{DS} = 30V$, $V_{GS} = 0V$	
I _{DSS}	Diaii-to-Source Leakage Current			250	μA	V _{DS} = 18V, V _{GS} = 0V, T _J = 150°C	
1	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 16V	
I _{GSS}	Gate-to-Source Reverse Leakage			-100	IIA	V _{GS} = -16V	
Qg	Total Gate Charge			50		I _D = 34A	
Q _{gs}	Gate-to-Source Charge			14	nC	$V_{DS} = 24V$	
Q _{gd}	Gate-to-Drain ("Miller") Charge			28		V _{GS} = 4.5V, See Fig. 6 and 13 ⊕ ⑦	
t _{d(on)}	Turn-On Delay Time		9.0			$V_{DD} = 15V$	
t _r	Rise Time		210		ns	$I_D = 34A$	
t _{d(off)}	Turn-Off Delay Time		20		115	$R_G = 3.4\Omega, V_{GS} = 4.5V$	
tf	Fall Time		54			$R_D = 0.43\Omega$, See Fig. 10 \oplus	
1-	Internal Drain Inductance		15		al I	Between lead,	
L _D	Internal Drain Inductance		4.5		nH	6mm (0.25in.)	
1	Internal Source Inductance		7.5			from package	
L _S	Internal Source inductance		7.5			and center of die contact®	
C _{iss}	Input Capacitance		1600			V _{GS} = 0V	
Coss	Output Capacitance		640		pF	$V_{DS} = 25V$	
C _{rss}	Reverse Transfer Capacitance		320			f = 1.0MHz, See Fig. 5	

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions			
Is	Continuous Source Current					MOSFET symbol			
	(Body Diode)			55®	Α	showing the			
I _{SM}	Pulsed Source Current			220	000	000	000		integral reverse
	(Body Diode) ①⑦					p-n junction diode.			
V _{SD}	Diode Forward Voltage			1.3	V	T _J = 25°C, I _S = 28A, V _{GS} = 0V ④			
t _{rr}	Reverse Recovery Time		81	120	ns	$T_J = 25^{\circ}C, I_F = 34A$			
Q _{rr}	Reverse RecoveryCharge		210	310	nC	di/dt = 100A/µs ④ ⑤			
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)							

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $V_{DD} = 15V, \text{ starting } T_J = 25^{\circ}C, L = 300 \mu H$ $R_G = 25 Ω, I_{AS} = 34A.$ (See Figure 12)
- $\begin{tabular}{l} @ I_{SD} \le 34A, \ di/dt \le 140A/\mu s, \ V_{DD} \le V_{(BR)DSS}, \\ T_{J} \le 175^{\circ}C \end{tabular}$
- 9 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$
- ⑤ Calculated continuous current based on maximum allowable junction temperature; Package limitation current = 20A
- $\mbox{\ \ }$ This is applied for I-PAK, LS of D-PAK is measured between lead and center of die contact
- ③ Uses IRL3103 data and test conditions
- ** When mounted on 1" square PCB (FR-4 or G-10 Material).
 For recommended footprint and soldering techniques refer to application note #AN-994
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IRLR/U3103PbF

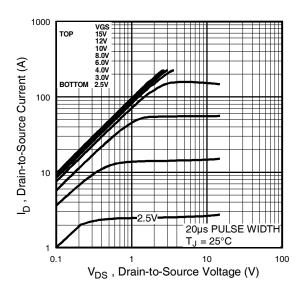
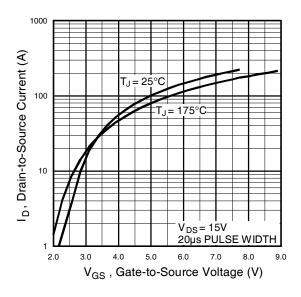


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics



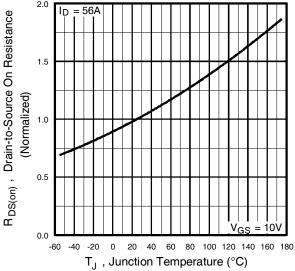


Fig 3. Typical Transfer Characteristics

Fig 4. Normalized On-Resistance Vs. Temperature

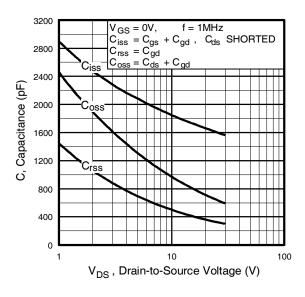


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

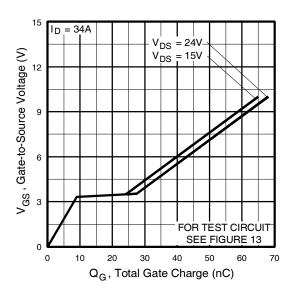


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

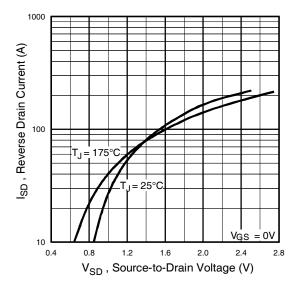


Fig 7. Typical Source-Drain Diode Forward Voltage

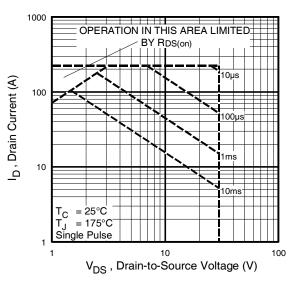


Fig 8. Maximum Safe Operating Area

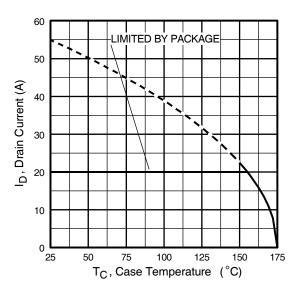


Fig 9. Maximum Drain Current Vs. Case Temperature

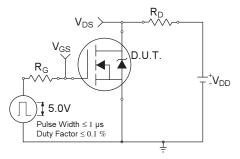


Fig 10a. Switching Time Test Circuit

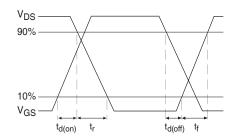


Fig 10b. Switching Time Waveforms

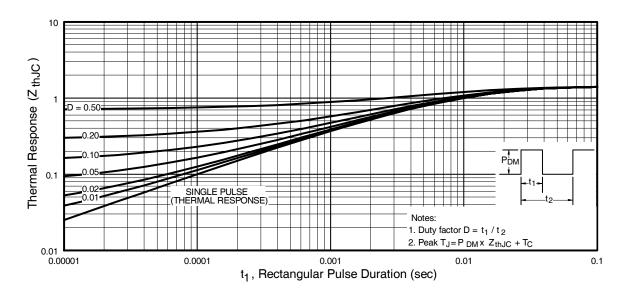


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

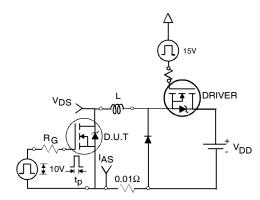


Fig 12a. Unclamped Inductive Test Circuit

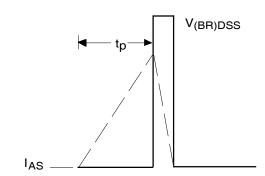


Fig 12b. Unclamped Inductive Waveforms

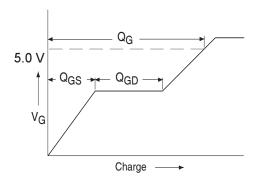


Fig 13a. Basic Gate Charge Waveform

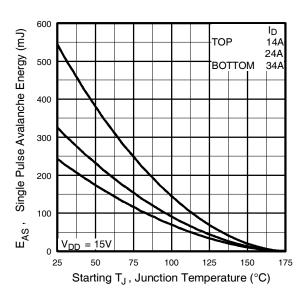


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

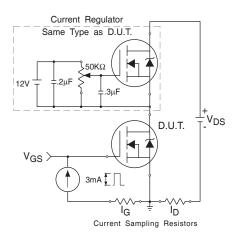
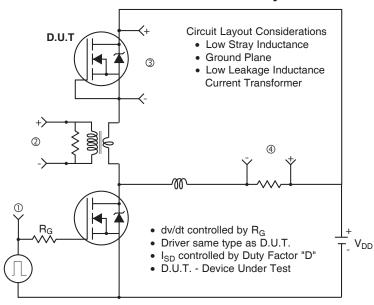


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



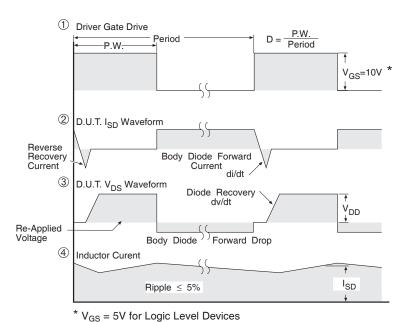


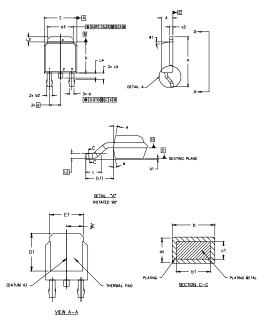
Fig 14. For N-Channel HEXFETS

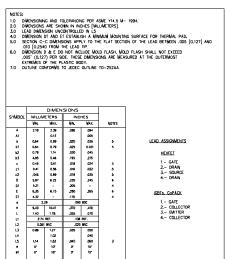
International

Rectifier

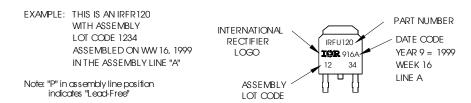
D-Pak (TO-252AA) Package Outline

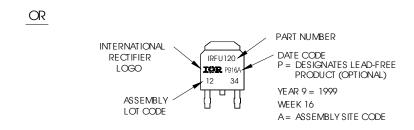
Dimensions are shown in millimeters (inches)





D-Pak (TO-252AA) Part Marking Information



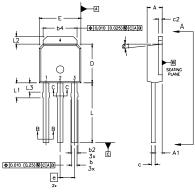


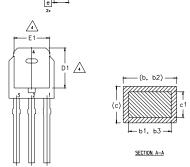
International IOR Rectifier

IRLR/U3103PbF

I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)





NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
- DIMENSIONING AND TOLERANDING PER ASME T14.5 M = 1994.

 DIMENSIONS ARE SHOWN IN MILEMETERS (INCHES) SOLD FLASH, SHALL NOT EXCEED

 OLOGS (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST

 EXTREMES OF THE PLASTIC BODY.

 THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1.

 LEAD DIMENSION UNCONTROLLED IN L3.

DIMENSION 61, 63 APPLY TO BASE METAL ONLY. OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA. CONTROLLING DIMENSION : INCHES.

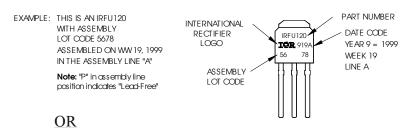
		DIMENSIONS						
SYMBOL	MILLIN	ETERS	INCHES					
	MIN.	MAX.	MIN.	MAX.	NOTES			
A	2.18	2.39	0.086	.094				
A1	0.89	1,14	0.035	0.045				
b	0.64	0.89	0.025	0.035				
ь1	0.64	0.79	0.025	0.031	4			
b2	0.76	1,14	0.030	0.045				
b3	0.76	1,04	0.030	0.041				
b4	5.00	5,46	0.195	0,215	4			
c	0.46	0,61	0.018	0.024				
c1	0.41	0.56	0.016	0.022				
c2	.046	0.86	0.018	0.035				
D	5.97	6.22	0,235	0,245	3, 4			
D1	5.21	- 1	0.205	-	4			
Ε	6.35	6.73	0.250	0.265	3, 4			
E1	4.32	-	0,170	-	4			
e	2.	2,29		0,090 BSC				
L	8.89	9.60	0.350	0.380	1			
L1	1.91	2.29	0.075	0.090				
L2	0.89	1,27	0,035	0,050	4			
L3	1,14	1,52	0.045	0,060	5			
01	0"	15"	o	15*				

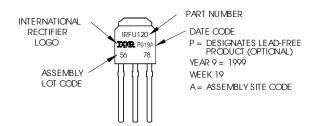
LEAD ASSIGNMENTS

HEXFET

1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN

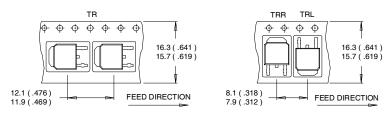
I-Pak (TO-251AA) Part Marking Information





D-Pak (TO-252AA) Tape & Reel Information

Dimensions are shown in millimeters (inches)



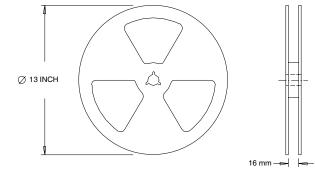
NOTES:

- NOTES.

 1. CONTROLLING DIMENSION : MILLIMETER.

 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).

 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:
1. OUTLINE CONFORMS TO EIA-481.

Data and specifications subject to change without notice.



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Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/

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